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AMIN, & TUROCY LLP.

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:

Applicant(s): Khoi A. Phan, et al.

John S. Ruggles

Serial No:

10/050,417

Art Unit:

Filing Date: January 16, 2002

Title:

METHODS AND SYSTEMS FOR CONTROLLING RESIST RESIDUE

DEFECTS AT GATE LAYER IN A SEMICONDUCTOR DEVICE

MANUFACTURING PROCESS

Mail Stop After Final Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

REPLY TO FINAL OFFICE ACTION DATED OCTOBER 23, 2003

Dear Sir:

Favorable reconsideration of the above-identified patent application is respectfully requested in view of the amendments and comments below.